## THIN FILM MEASUREMENT EQUIPMENT



## Dektak Surface Profile Measurement System

The Sloan Dektak is a compact, highly sensitive instrument used for the precise measurement of very small vertical dimensions. It has found wide application in the measurement of thin films from 25 to 1,000,000 angstroms in thickness.

The Dektak is most frequently used for the determination of the surface profiles of evaporated, sputtered, or chemically deposited thin films, the profiles of etched oxide patterns and photoresist masks, and the surface characteristics of substrates before deposition.

The Dektak measures a surface profile by scanning the sample with a diamond stylus at approximately 15 milligrams tracking force. A microscope with integral illumination enables the operator to view the scan area. Three scanning speeds are available in addition to manual rapid forward and reverse. Vertical scan magnification can be selected from seven levels ranging from 1,000X to 1,000,000X. An optional range doubler is available.

The instrument is compact, rugged, and simple to operate. It is fully portable, requiring only conventional AC main power, and is able to function in a normal industrial environment with no special facilities.

The Dektak measurements are recorded on a Sloan three-speed chart recorder. In conjunction with the available Dektak scan speeds, the recorder is capable of displaying nine horizontal magnifications ranging from 2X to 5,000X.

## **SPECIFICATIONS**

Dektak®

Measurement Ranges

Vertical magnifications . . . . . 1,000X to 1,000,000X in 7 steps (1,000,000 to 1,000 Å full scale)

Maximum Sample Thickness . . . . . . . 1 inch Power Required . . . . . . 120 vac, 50/60 Hz, 1 ampere

